Application/Control No. Applicant(s)/Patent Under Reexamination 10/791,740 HEO ET AL. Notice of References Cited Examiner Art Unit Page 1 of 1 DuyVu n. Deo 1765 **U.S. PATENT DOCUMENTS** Document Number Date Classification Name Country Code-Number-Kind Code MM-YYYY US-6,326,282 12-2001 Park et al. 438/424 Α US-В US-С US-D US-Ε US-F US-G US-Н US-US-J US-Κ US-L US-М FOREIGN PATENT DOCUMENTS **Document Number** Date Country Name Classification Country Code-Number-Kind Code MM-YYYY Ν 0 Р Q R S Т **NON-PATENT DOCUMENTS** Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages) U W

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